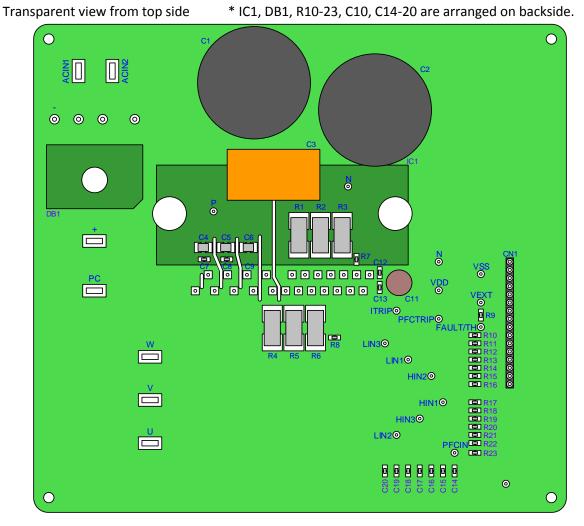
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# Test Procedure for the STK5MFU3C1AGEVB Evaluation Board

### Description of each pin



U, V, W : 3 phase inverter output VDD : Control power supply (DC15V) VSS : Signal GND PC : Rectified AC voltage input HINx, LINx, PFCIN : Control signal input ITRIP : Over-current protection for Inverter PFCTRIP : Over-current protection for PFC VEXT : FAULT/TH pull-up

Apply the logic I/O voltage **FAULT/TH** : Fault output, Thermistor **ACIN1, ACIN2** : Bridge diode AC voltage input +, - : Bridge diode output

- R1-6 : Shunt resistor, 3 parallel connection
- R7 (, C12) : RC filter for ITRIP
- R8 (, C13) : RC filter for PFCTRIP
- **R9** : Pull-up to VEXT (FAULT/TH)
- R10-16, C14-20 : Low pass filter for signal input Prevention malfunction by noise
- R17-23 : Pull-down to VSS for signal input Prevention malfunction by external wiring
- C4-6 : Boot strap capacitor

## Blue : Arranged on top side Purple : Arranged on back side

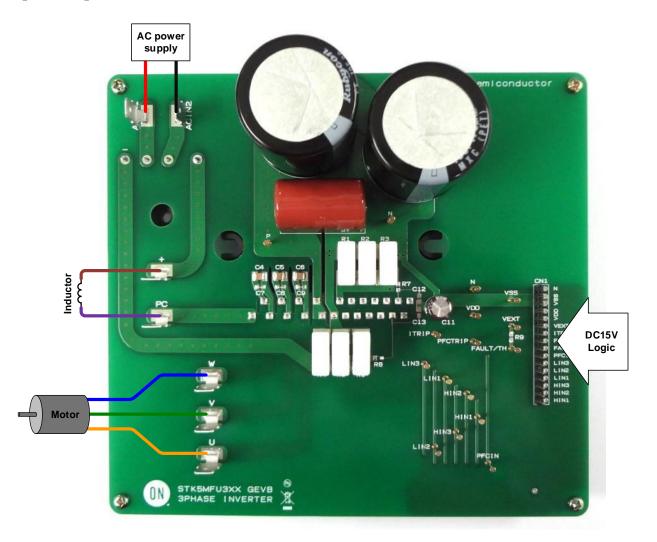
\* C10 is arranged on back position of C12 and C13

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### **Operation procedure**



- **Step1**: Connect IPM, the three power supplies, logic parts, inductor and the motor to the evaluation board, and confirm that each power supply is OFF at this time.
- **Step2**: Apply DC15V to VDD and the logic I/O voltage to VEXT.
- **Step3**: Perform a voltage setup according to specifications, and apply AC power supply between ACIN1 and ACIN2.
- **Step4**: The IPM will start when signals are applied. The low-side inputs must be switched on first to charge up the bootstrap capacitors.
- Note : When turning off the power supply part and the logic part, please carry out in the reverse order to above steps.